

- **8-Bit Resolution A/D Converter**
- **Microprocessor Peripheral or Stand-Alone Operation**
- **On-Chip 12-Channel Analog Multiplexer**
- **Built-In Self-Test Mode**
- **Software-Controllable Sample and Hold**
- **Total Unadjusted Error . . . ± 0.5 LSB Max**
- **Direct Replacement for Motorola MC145041**
- **Onboard System Clock**
- **End-of-Conversion (EOC) Output**
- **Pinout and Control Signals Compatible With the TLC1542/3 10-Bit A/D Converters**
- **CMOS Technology**

| PARAMETER | VALUE |
|---------------------------------|------------------|
| Channel Acquisition/Sample Time | 16 μ s |
| Conversion Time (Max) | 20 μ s |
| Samples per Second (Max) | 25×10^3 |
| Power Dissipation (Max) | 10 mW |

description

The TLC542 is a CMOS converter built around an 8-bit switched-capacitor successive-approximation analog-to-digital converter. The device is designed for serial interface to a microprocessor or peripheral via a 3-state output with three inputs [including I/O CLOCK, \overline{CS} (chip select), and ADDRESS INPUT]. The TLC542 allows high-speed data transfers and sample rates of up to 40,000 samples per second. In addition to the high-speed converter and versatile control logic, an on-chip 12-channel analog multiplexer can sample any one of 11 inputs or an internal *self-test* voltage, and the sample and hold is started under microprocessor control. At the end of conversion, the end-of-conversion (EOC) output pin goes high to indicate that conversion is complete.

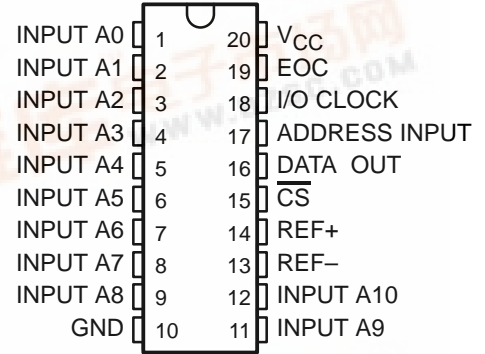
The converter incorporated in the TLC542 features differential high-impedance reference inputs that facilitate ratiometric conversion, scaling, and isolation of analog circuitry from logic and supply noises. A switched-capacitor design allows low-error (± 0.5 LSB) conversion in 20 μ s over the full operating temperature range.

The TLC542C is characterized for operation from 0°C to 70°C and the TLC542I is characterized for operation from -40°C to 85°C.

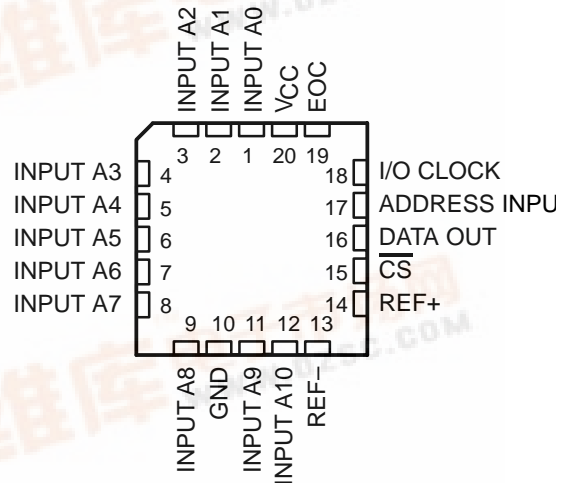
AVAILABLE OPTIONS

| T _A | PACKAGE | | |
|----------------|-------------------|-----------------|--------------------|
| | CHIP CARRIER (FN) | PLASTIC DIP (N) | SMALL OUTLINE (DW) |
| 0°C to 70°C | — | TLC542CN | TLC542CDW |
| -40°C to 85°C | TLC542IFN | TLC542IN | TLC542IDW |

DW OR N PACKAGE (TOP VIEW)



FN PACKAGE (TOP VIEW)



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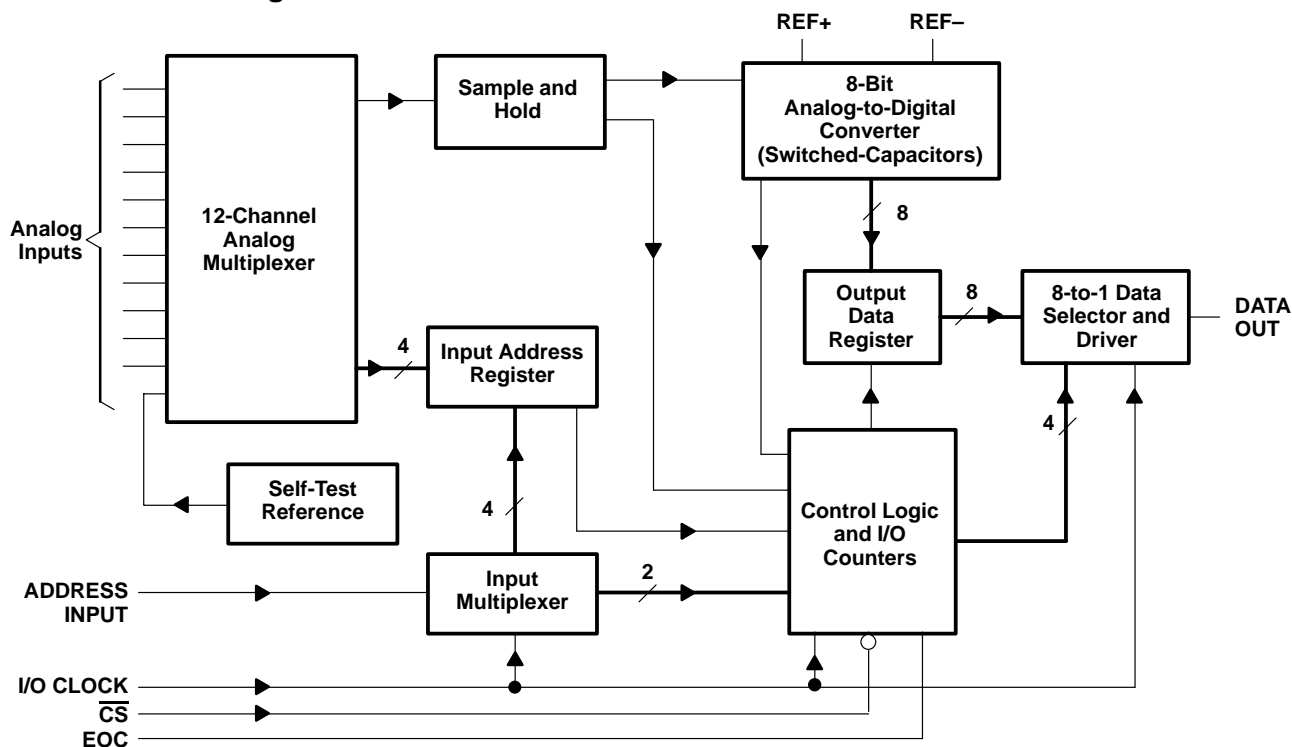
TLC542C, TLC542I

8-BIT ANALOG-TO-DIGITAL CONVERTERS

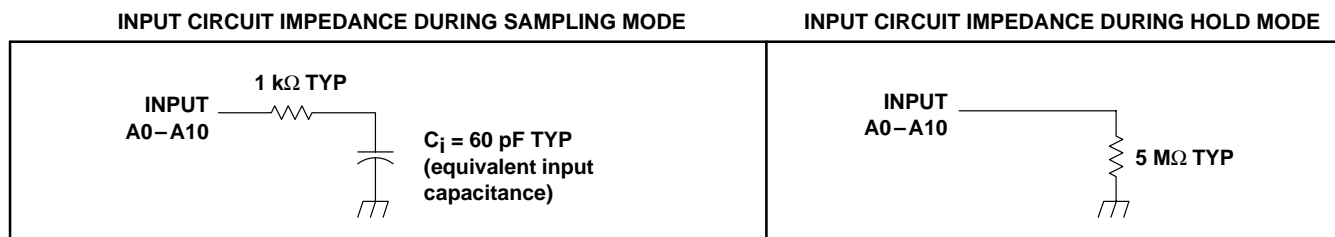
WITH SERIAL CONTROL AND 11 INPUTS

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functional block diagram



typical equivalent inputs

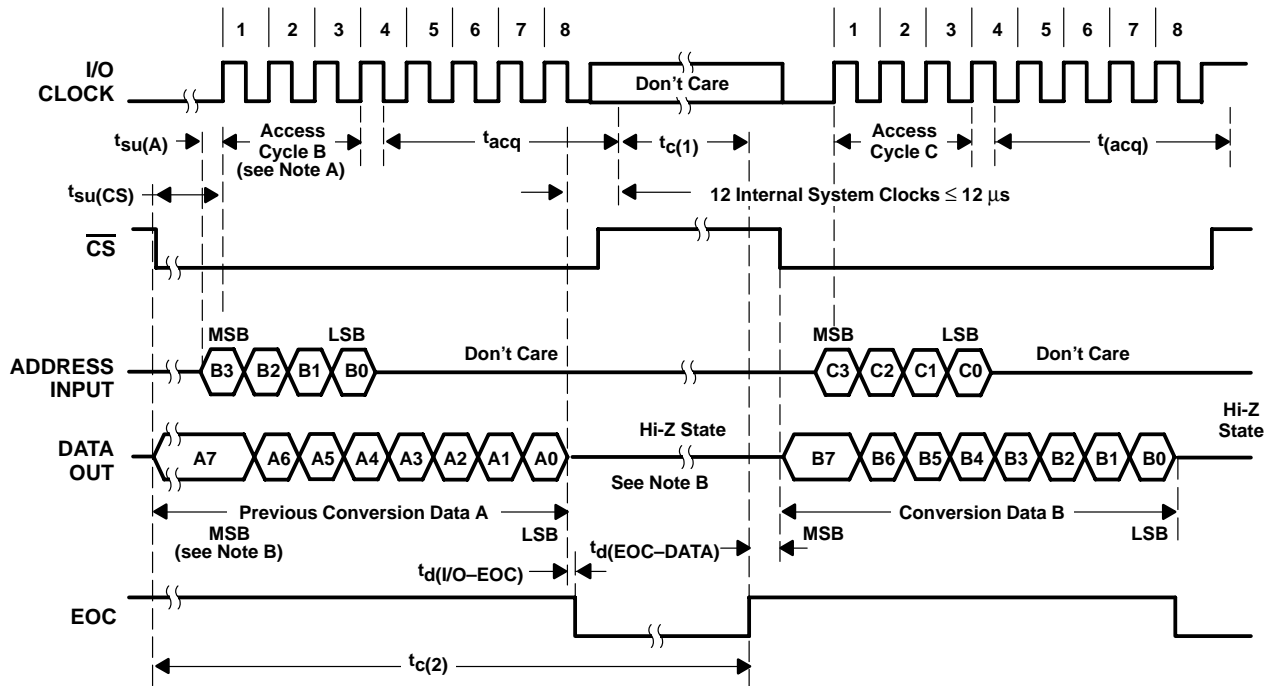


TLC542C, TLC542I

8-BIT ANALOG-TO-DIGITAL CONVERTERS WITH SERIAL CONTROL AND 11 INPUTS

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operating sequence



- NOTES: A. To minimize errors caused by noise at the chip select input, the internal circuitry waits for two rising edges and one falling edge of the internal system clock after \overline{CS} before responding to control input signals. The \overline{CS} setup time is given by the $t_{su}(CS)$ specifications. Therefore, no attempt should be made to clock-in an address until the minimum chip select setup time has elapsed.
- B. The output becomes 3-state on \overline{CS} going high or on the negative edge of the eighth I/O clock.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

| | |
|---|----------------------------|
| Supply voltage, V_{CC} (see Note 1) | 6.5 V |
| Input voltage range (any input) | -0.3 V to $V_{CC} + 0.3$ V |
| Output voltage range, V_O | -0.3 V to $V_{CC} + 0.3$ V |
| Peak input current range (any input), I_{p-p} | ± 20 mA |
| Peak total input current (all inputs), I_P | ± 30 mA |
| Operating free-air temperature range: TLC542C | 0°C to 70°C |
| TLC542I | -40°C to 85°C |
| Storage temperature range, T_{stg} | -65°C to 150°C |
| Case temperature for 10 seconds, T_C : FN package | 260°C |
| Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: DW or N package | 260°C |

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to digital ground with REF- and GND wired together (unless otherwise noted).

TLC542C, TLC542I

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recommended operating conditions, $V_{CC} = 4.75$ to 5.5 V

| | MIN | NOM | MAX | UNIT |
|---|-------------------------------|----------|----------------|--------------|
| Supply voltage, V_{CC} | 4.75 | 5 | 5.5 | V |
| Positive reference voltage, V_{ref+} (see Note 2) | V_{ref-} | V_{CC} | $V_{CC} + 0.1$ | V |
| Negative reference voltage, V_{ref-} (see Note 2) | -0.1 | 0 | V_{ref+} | V |
| Differential reference voltage, $V_{ref+} - V_{ref-}$ (see Note 2) | 1 | V_{CC} | $V_{CC} + 0.2$ | V |
| Analog input voltage (see Note 3) | 0 | | V_{CC} | V |
| High-level control input voltage, V_{IH} | 2 | | | V |
| Low-level control input voltage, V_{IL} | | | 0.8 | V |
| Setup time, address bits at data input before I/O CLOCK \uparrow , $t_{su(A)}$ | 400 | | | ns |
| Hold time, address bits after I/O CLOCK \uparrow , $t_h(A)$ | 0 | | | ns |
| Hold time, \overline{CS} low after 8th I/O CLOCK \uparrow , $t_h(CS)$ | 0 | | | ns |
| Setup time, \overline{CS} low before clocking in first address bit, $t_{su(CS)}$ (see Note 4) | 3.8 | | | μ s |
| Input/output clock frequency, $f_{(clock\ I/O)}$ | 0 | 1.1 | | MHz |
| Input/output clock high, $t_{w(H\ I/O)}$ | 404 | | | ns |
| Input/output clock low, $t_{w(L\ I/O)}$ | 404 | | | ns |
| I/O CLOCK transition time, t_t (see Note 3) | $f_{clock(I/O)} \leq 525$ kHz | | 100 | ns |
| | $f_{clock(I/O)} > 525$ kHz | | 40 | |
| Operating free-air temperature, T_A | TLC542C | | 0 | $^{\circ}$ C |
| | TLC542I | | -40 | |

- NOTES: 2. Analog input voltages greater than that applied to REF+ convert as all ones (11111111), while input voltages less than that applied to REF- convert as all zeros (00000000). For proper operation, REF+ must be at least 1 V higher than REF-. Also, the total unadjusted error may increase as this differential reference voltage falls below 4.75 V.
3. This is the time required for the clock input signal to fall from V_{IH} min to V_{IL} max or to rise from V_{IL} max to V_{IH} min. In the vicinity of normal room temperature, the devices function with input clock transition time as slow as 2 μ s for remote data acquisition applications where the sensor and the A/D converter are placed several feet away from the controlling microprocessor.
4. To minimize errors caused by noise at the chip select input, the internal circuitry waits for two rising edges and one falling edge of the internal system clock after \overline{CS} \downarrow before responding to control input signals. The \overline{CS} setup time is given by the $t_{su(CS)}$ specifications. Therefore, no attempt should be made to clock-in address data until the minimum chip select setup time has elapsed.

electrical characteristics over recommended operating temperature range, $V_{CC} = V_{ref+} = 4.75$ V to 5.5 V, $f_{(clock\ I/O)} = 1.1$ MHz (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP \dagger | MAX | UNIT |
|-----------|---|--|-----|---------------|------|---------|
| V_{OH} | High-level output voltage (DATA OUT) | $V_{CC} = 4.75$ V, $I_{OH} = -360$ μ A | 2.4 | | | V |
| V_{OL} | Low-level output voltage | $V_{CC} = 4.75$ V, $I_{OL} = 1.6$ mA | | | 0.4 | V |
| | Off-state (high-impedance state) output current | $V_O = V_{CC}$, \overline{CS} at V_{CC} | | | 10 | μ A |
| | | $V_O = 0$, \overline{CS} at V_{CC} | | | -10 | |
| I_{IH} | High-level input current | $V_I = V_{CC}$ | | 0.005 | 2 | μ A |
| I_{IL} | Low-level input current | $V_I = 0$ | | -0.005 | -2.5 | μ A |
| I_{CC} | Operating supply current | \overline{CS} at 0 V | | 1.2 | 2 | mA |
| | Selected channel leakage current | Selected channel at V_{CC} and unselected channel at 0 V | | | 0.4 | μ A |
| | | Selected channel at 0 V and unselected channel at V_{CC} | | | -0.4 | |
| I_{ref} | Maximum static analog reference current into REF+ | $V_{ref+} = V_{CC}$, $V_{ref-} = GND$ | | | 10 | μ A |
| C_i | Input capacitance | Analog inputs | | 7 | 55 | pF |
| | | Control inputs | | 5 | 15 | |

\dagger All typical values are at $T_A = 25^{\circ}$ C.

TLC542C, TLC542I
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operating characteristics over recommended operating free-air temperature range,
 $V_{CC} = V_{ref+} = 4.75$ to 5.5 V, $f_{(clock\ I/O)} = 1$ MHz

| PARAMETER | TEST CONDITIONS | MIN | TYP† | MAX | UNIT |
|--------------------|---|---|-------------------|-------------------|------|
| E_L | Linearity error (see Note 5) | | | ±0.5 | LSB |
| E_{ZS} | Zero-scale error (see Note 6) | See Note 2 | | ±0.5 | LSB |
| E_{FS} | Full-scale error (see Note 6) | See Note 2 | | ±0.5 | LSB |
| | Total unadjusted error (see Note 7) | | | ±0.5 | LSB |
| | Self-test output code | Input A11 address = 1011, See Note 8 | 01111101 (126) | 10000011 (130) | |
| $t_c(1)$ | Conversion time | See operating sequence | | 20 | μs |
| $t_c(2)$ | Total access and conversion cycle time | See operating sequence | | 40 | μs |
| $t_{(acq)}$ | Channel acquisition time (sample cycle) | See operating sequence | | 16 | μs |
| $t_{(v)}$ | Time output data remains valid after I/O CLK↓ | See Figure 5 | 10 | | ns |
| $t_{d(I/O-DATA)}$ | Delay time, I/O CLK↓ to data output valid | See Figure 5 | | 400 | ns |
| $t_{d(I/O-EOC)}$ | Delay time, 8th I/O CLK↓ to EOC↓ | See Figure 6 | | 500 | ns |
| $t_{d(EOC-DATA)}$ | Delay time, EOC↑ to data out (MSB) | See Figure 7 | | 400 | ns |
| t_{PHZ}, t_{PZL} | Delay time, CS↓ to data out (MSB) | See Figure 2 | | 3.4 | μs |
| t_{PHZ}, t_{PLZ} | Delay time, CS↑ to data out (MSB) | See Figure 2 | | 150 | ns |
| $t_r(EOC)$ | Rise time | See Figure 7 | | 100 | ns |
| $t_f(EOC)$ | Fall time | See Figure 6 | | 100 | ns |
| $t_r(\text{bus})$ | Data bus rise time | See Figure 5 | | 300 | ns |
| $t_f(\text{bus})$ | Data bus fall time | See Figure 5 | | 300 | ns |

† All typical values are at $T_A = 25^\circ\text{C}$.

- NOTES: 2. Analog input voltages greater than that applied to REF+ convert to all ones (11111111), while input voltages less than that applied to REF- convert to all zeros (00000000). For proper operation, REF+ must be at least 1 V higher than REF-. Also, the total unadjusted error may increase as this differential reference voltage falls below 4.75 V.
5. Linearity error is the maximum deviation from the best straight line through the A/D transfer characteristics.
6. Zero-scale error is the difference between 00000000 and the converted output for zero input voltage; full-scale error is the difference between 11111111 and the converted output for full-scale input voltage.
7. Total unadjusted error is the sum of linearity, zero-scale, and full-scale errors.
8. Both the input address and the output codes are expressed in positive logic. The A11 analog input signal is internally generated and is used for test purposes.

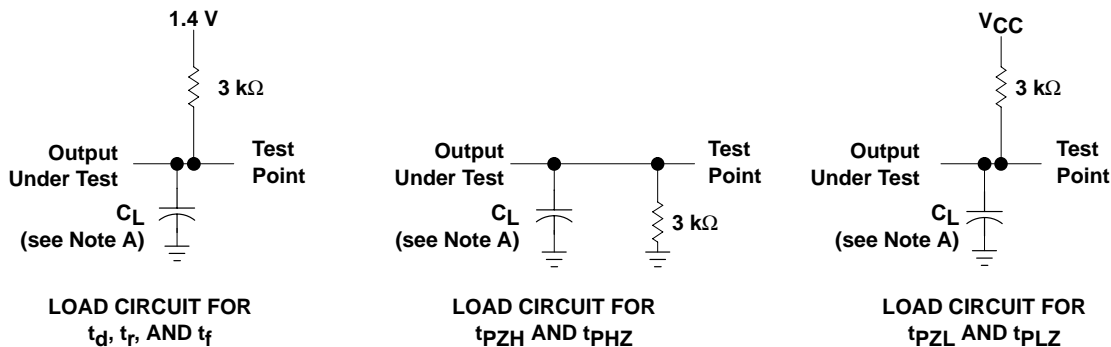
TLC542C, TLC542I

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WITH SERIAL CONTROL AND 11 INPUTS

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PARAMETER MEASUREMENT INFORMATION



NOTE A: $C_L = 50 \text{ pF}$

Figure 1. Load Circuits

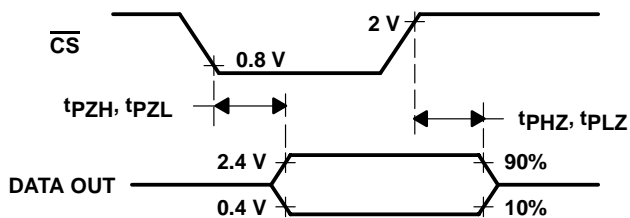


Figure 2. $\overline{\text{CS}}$ to Data Output Timing

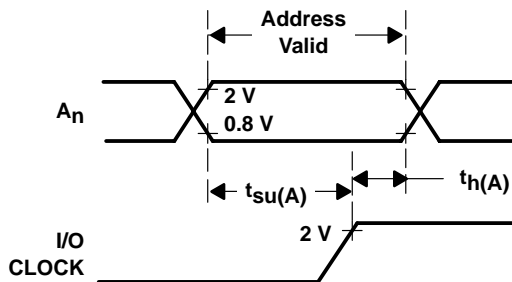


Figure 3. Address Timing

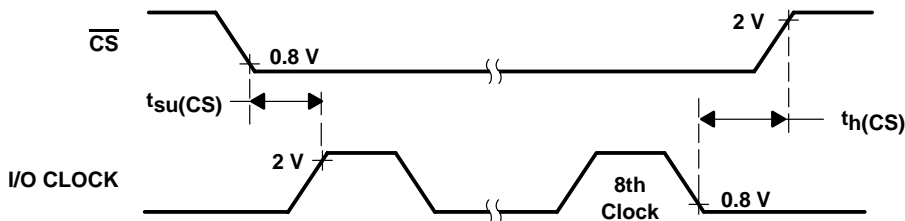


Figure 4. $\overline{\text{CS}}$ to I/O CLOCK Timing

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PARAMETER MEASUREMENT INFORMATION

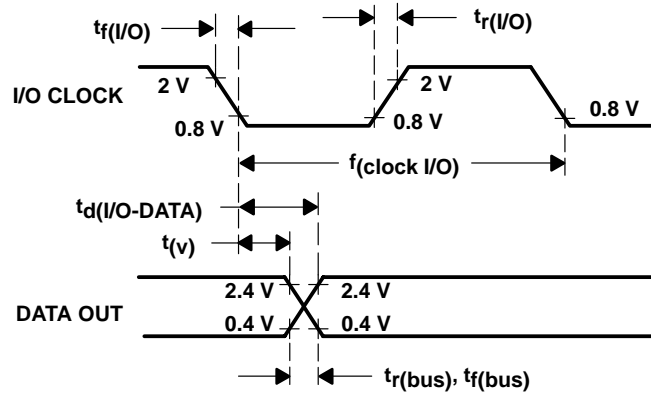


Figure 5. Data Output Timing

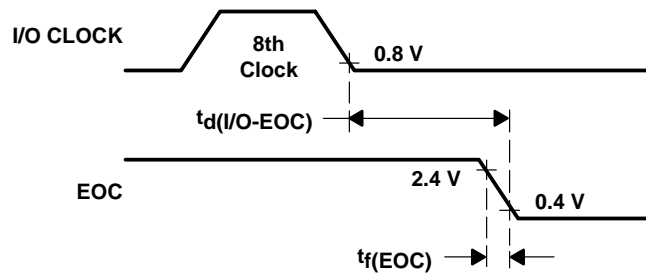


Figure 6. EOC Timing

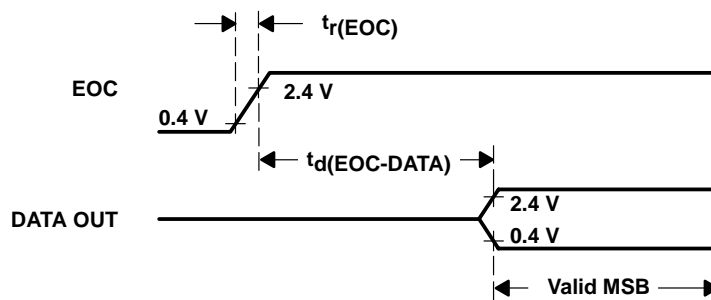


Figure 7. Data Output to EOC Timing

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APPLICATION INFORMATION

simplified analog input analysis

Using the equivalent circuit in Figure 8, the time required to charge the analog input capacitance from 0 to V_S within 1/2 LSB can be derived as follows:

The capacitance charging voltage is given by

$$V_C = V_S (1 - e^{-t_c/R_t C_i}) \tag{1}$$

where

$$R_t = R_s + r_i$$

The final voltage to 1/2 LSB is given by

$$V_C (1/2 \text{ LSB}) = V_S - (V_S/512) \tag{2}$$

Equating equation 1 to equation 2 and solving for time t_c gives

$$V_S - (V_S/512) = V_S (1 - e^{-t_c/R_t C_i}) \tag{3}$$

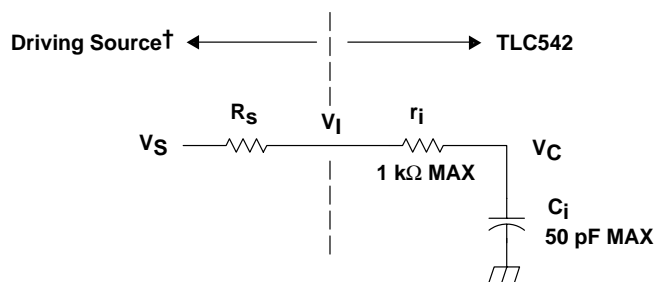
and

$$t_c (1/2 \text{ LSB}) = R_t \times C_i \times \ln(512) \tag{4}$$

Therefore, with the values given the time for the analog input signal to settle is

$$t_c (1/2 \text{ LSB}) = (R_s + 1 \text{ k}\Omega) \times 60 \text{ pF} \times \ln(512) \tag{5}$$

This time must be less than the converter sample time shown in the timing diagrams.



V_I = Input Voltage at INPUT A0–A10
 V_S = External Driving Source Voltage
 R_S = Source Resistance
 r_i = Input Resistance
 C_i = Input Capacitance

† Driving source requirements:

- Noise and distortion for the source must be equivalent to the resolution of the converter.
- R_S must be real at the input frequency.

Figure 8. Equivalent Input Circuit Including the Driving Source

PRINCIPLES OF OPERATION

The TLC542 is a complete data acquisition system on a single chip. The device includes such functions as analog multiplexer, sample and hold, 8-bit A/D converter, data and control registers, and control logic. Three control inputs (I/O CLOCK, \overline{CS} (chip select), and ADDRESS INPUT) are included for flexibility and access speed. These control inputs and a TTL-compatible 3-state output are intended for serial communications with a microprocessor or microcomputer. With judicious interface timing, the TLC542 can complete a conversion in 20 μ s, while complete input-conversion-output cycles can be repeated every 40 μ s. Furthermore, this fast conversion can be executed on any of 11 inputs or its built-in self-test and in any order desired by the controlling processor.

When \overline{CS} is high, the DATA OUT terminal is in a 3-state condition, and the ADDRESS INPUT and I/O CLOCK terminals are disabled. When additional TLC542 devices are used, this feature allows each of these terminals, with the exception of the \overline{CS} terminal, to share a control logic point with their counterpart terminals on additional A/D devices. Thus, this feature minimizes the control logic terminals required when using multiple A/D devices.

The control sequence is designed to minimize the time and effort required to initiate conversion and obtain the conversion result. A normal control sequence is as follows:

1. \overline{CS} is brought low. To minimize errors caused by noise at the \overline{CS} input, the internal circuitry waits for two rising edges and then a falling edge of the internal system clock before recognizing the low \overline{CS} transition. The MSB of the result of the previous conversion automatically appears on the DATA OUT terminal.
2. On the first four rising edges of the I/O CLOCK, a new positive-logic multiplexer address is shifted in, with the MSB of this address shifted first. The negative edges of these four I/O CLOCK pulses shift out the second, third, fourth, and fifth most significant bits of the result of the previous conversion. The on-chip sample and hold begins sampling the newly addressed analog input after the fourth falling edge of the I/O CLOCK. The sampling operation basically involves charging the internal capacitors to the level of the analog input voltage.
3. Three clock cycles are applied to the I/O CLOCK terminal and the sixth, seventh, and eighth conversion bits are shifted out on the negative edges of these clock cycles.
4. The final eighth clock cycle is applied to the I/O CLOCK terminal. The falling edge of this clock cycle initiates a 12-system clock ($\approx 12 \mu$ s) additional sampling period while the output is in the high-impedance state. Conversion is then performed during the next 20 μ s. After this final I/O CLOCK cycle, \overline{CS} must go high or the I/O CLOCK must remain low for at least 20 μ s to allow for the conversion function.

\overline{CS} can be kept low during periods of multiple conversion. If \overline{CS} is taken high, it must remain high until the end of conversion. Otherwise, a valid falling edge of \overline{CS} causes a reset condition, which aborts the conversion process.

A new conversion may be started and the ongoing conversion simultaneously aborted by performing steps 1 through 4 before the 20- μ s conversion time has elapsed. Such action yields the conversion result of the previous conversion and not the ongoing conversion.

The end-of-conversion (EOC) output goes low on the negative edge of the eighth I/O CLOCK. The subsequent low-to-high transition of EOC indicates the A/D conversion is complete and the conversion is ready for transfer.

PACKAGING INFORMATION

| Orderable Device | Status ⁽¹⁾ | Package Type | Package Drawing | Pins | Package Qty | Eco Plan ⁽²⁾ | Lead/Ball Finish | MSL Peak Temp ⁽³⁾ |
|------------------|-----------------------|--------------|-----------------|------|-------------|-------------------------|------------------|---|
| TLC542CDW | ACTIVE | SOIC | DW | 20 | 25 | Pb-Free (RoHS) | CU NIPDAU | Level-2-250C-1YEAR/ Level-1-220C-UNLIM |
| TLC542CDWR | ACTIVE | SOIC | DW | 20 | 2000 | Pb-Free (RoHS) | CU NIPDAU | Level-2-250C-1YEAR/ Level-1-220C-UNLIM |
| TLC542CN | ACTIVE | PDIP | N | 20 | 20 | Pb-Free (RoHS) | CU NIPDAU | Level-NA-NA-NA |
| TLC542IDW | ACTIVE | SOIC | DW | 20 | 25 | Pb-Free (RoHS) | CU NIPDAU | Level-2-250C-1YEAR/ Level-1-220C-UNLIM |
| TLC542IDWR | ACTIVE | SOIC | DW | 20 | 2000 | Pb-Free (RoHS) | CU NIPDAU | Level-2-250C-1YEAR/ Level-1-220C-UNLIM |
| TLC542IFN | ACTIVE | PLCC | FN | 20 | 46 | None | Call TI | Call TI |
| TLC542IFNR | ACTIVE | PLCC | FN | 20 | 1000 | None | Call TI | Call TI |
| TLC542IN | ACTIVE | PDIP | N | 20 | 20 | Pb-Free (RoHS) | CU NIPDAU | Level-NA-NA-NA |

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBsolete: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - May not be currently available - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.

None: Not yet available Lead (Pb-Free).

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Green (RoHS & no Sb/Br): TI defines "Green" to mean "Pb-Free" and in addition, uses package materials that do not contain halogens, including bromine (Br) or antimony (Sb) above 0.1% of total product weight.

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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